

EAST Search History

10/614,997

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	829	process\$3 and (test result\$1 same first test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 14:31
L2	46	execut\$3 and (second test same concurrently or parallel same processing test data)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 14:56
L3	7	L1 and L2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 14:31
L4	21738	717/124 or 717/115 or 714/127 or 717/131 or 714/724 or 714/38 or "7141" or 714/1 or 714/725 or 714/30 or 714/733 or 714/734 or 714/757 or 714/799 or 365/201 or 714/?	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 14:55
L5	24046	703/4 or 702/? or I4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 14:55
L6	43	execut\$3 and (second test same concurrently or parallel same processing first test data)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 14:56
L7	7	I6 and I1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 14:56
L8	2	I7 and I5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 15:04

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L9	1	("4672534").PN.	US-PGPUB; USPAT	OR	OFF	2006/05/09 15:04
L10	14665	mixed signal\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 15:04
L11	571720	semiconductor device	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 15:04
L14	829	process\$3 and (test result\$1 same first test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 15:12
L15	46	execut\$3 and (second test same concurrently or parallel same processing test data)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 15:12
L16	44	execut\$3 and (second test same concurrently or parallel same processing test result\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 15:12
L17	47	L15 or L16	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 15:12
L18	7	L17 and L14	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 15:12
L19	571720	semiconductor device	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 15:12

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L20	4	L18 and L19	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 15:12
L21	29	mixed signal semiconductor device	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 16:15
L22	7	(("20020080811") or ("20020183426") or ("20030004669") or ("20030004670") or ("20030005172") or ("20030005180") or ("20030058280")).PN.	US-PGPUB; USPAT	OR	OFF	2006/05/09 16:05
L23	18	(("5.063.383") or ("5.504.917") or ("5.629.632") or ("5.821.440") or ("5.821.934") or ("5.923.567") or ("5.926.774") or ("5.963.726") or ("6.031.387") or ("6.040.700") or ("6,085,156") or ("6,104,721") or ("6.128.759") or ("6.192.496") or ("6223134") or ("6347287") or ("6401220") or ("6405145") or ("6418392") or ("6421822") or ("6442441") or ("6449744") or ("6473707") or ("6546359") or ("6560554") or ("6577981") or ("6618853") or ("20030005155") or ("20030135343") or ("20030177426")).PN.	US-PGPUB; USPAT	OR	OFF	2006/05/09 15:53
L27	27	test head same l10	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 16:15
L28	123318	tester\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 16:15

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L29	21	I27 and I28	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 16:16
L30	9	I19 and I29	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 16:16
L31	13989	test processor or test program	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 16:16
L32	5	I30 and I31	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/05/09 16:16